

Role of boron in amorphous SiBCN and nanocomposite MSiBCN

Jiri Houska

*Department of Physics and NTIS - European Centre of Excellence,
University of West Bohemia, Plzen (Pilsen), Czech Republic*



Role of boron in amorphous SiBCN and nanocomposite MSiBCN

Jiri Houska

*Department of Physics and NTIS - European Centre of Excellence,
University of West Bohemia, Plzen (Pilsen), Czech Republic*

Acknowledgment (2001-2017)

- J. Capek, R. Cerstvy, J. Cizek, S. Hreben, J. Kalas, J. Kohout, M. Kormunda, S. Kos, P. Mares, J. Martan, V. Perina, V. Petrman, S. Potocky, V. Simova, P. Steidl, J. Vlcek, P. Zeman, S. Zuzjakova (*University of West Bohemia in Plzen*)
- M. Bilek et al. (*Sydney*), L. Martinu et al. (*Montreal*), E.I. Meletis et al. (*Arlington*)

Predecessors and motivation

■ SiCN and BCN films (1990's):

- controllable properties of SiCN such as hardness or thermal stability, but not as good as after B incorporation
- high compressive stress of BCN

■ SiBCN by pyrolysis

[R. Riedel et al., A silicoboron carbonitride ceramic stable to 2000 °C, Nature 382, 796 (1996)]

■ SiBCN films

[J. Vlcek et al., J. Vac. Sci. Technol. A 23, 1513 (2005)] : first paper on sputtered SiBCN

[J. Houska, Ceram. Int. 41, 7921 (2015)] : includes recent overview on sputtered SiBCN

- amorphous structure stable up to a 1700 °C limit
- extremely high oxidation resistance in air above 1500 °C
- high H up to 44 GPa and $E/(1-\nu^2)$ up to 240 GPa
- controllable $E_g = 0$ to 3.5 eV \Rightarrow transparency ($k_{550\text{nm}} = 2 \times 10^{-4}$)
or finite resistivity ($\sim 10^1 \Omega\text{m}$) depending on composition

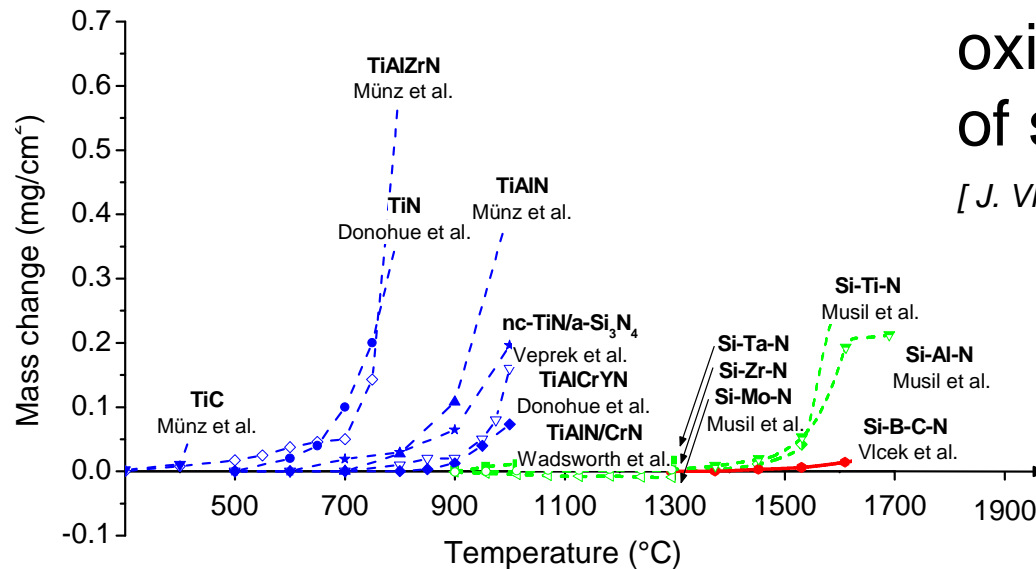
■ MSiBCN films

[M. Zhang et al., Appl. Surf. Sci. 357, 1343 (2015)] : example for $M = \text{Hf}$

[J. Houska et al., Ceram. Int. 42, 4361 (2016)] : example for $M = \text{Zr}$

- wider range of structures, e.g. MB_2 -based
- wider range of properties, e.g. resistivity of "interesting" compositions
SiBCN: from insulating to $\sim 10^1 \Omega\text{m}$ (SiBCN), $\sim 10^{-1} \Omega\text{m}$ (N-free SiBC)
MSiBCN: from insulating to $\sim 10^{-6} \Omega\text{m}$

Predecessors and motivation

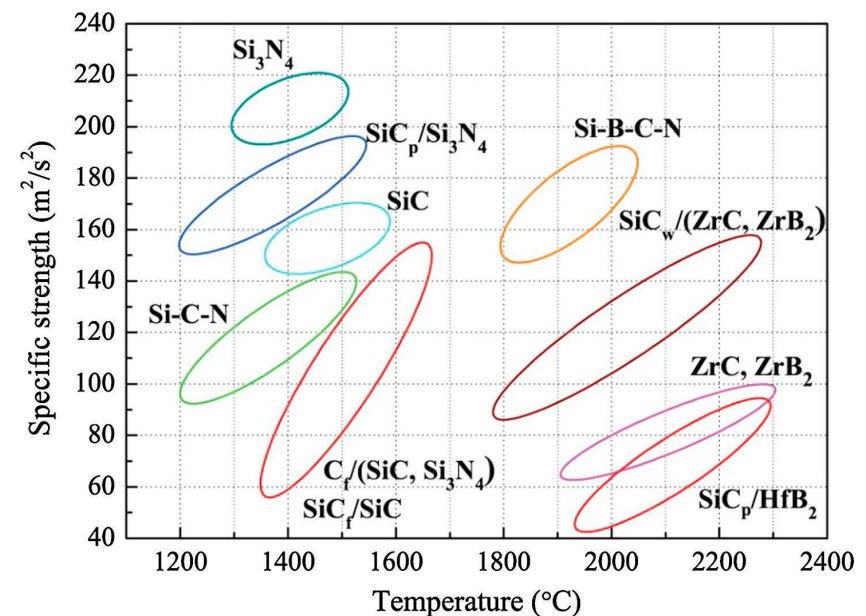


oxidation resistance
of sputtered SiBCN

[J. Vlcek et al., J. Vac. Sci. Technol. A 23, 1513 (2005), etc.]

specific strength and working
temperature of SiBCN

[D. Jia et al., Prog. Mater. Sci. 98, 1 (2018)]



Boron-focused outline

Phenomena relevant for amorphous **SiBCN**

(including amorphous matrix of nanocomposite MSiBCN)

1-1 : effect of B content: thermal stability, hardness

1-2 : high compressive stress of BCN: how to decrease it

1-3 : homogeneous networks \times formation of B-rich zones

1-4 : high- T oxidation: h-BN between bulk and surface oxide

1-5 : room- T oxidation: effect of B content on ageing resistance

Phenomena relevant only for **MSiBCN**

2-1 : crystalline phases obtained: h-MB₂, fcc-MB_xN_{1-x}

2-2 : effect of crystallinity: electrical and thermal conductivity

2-3 : high compressive stress of MB₂: how to decrease it

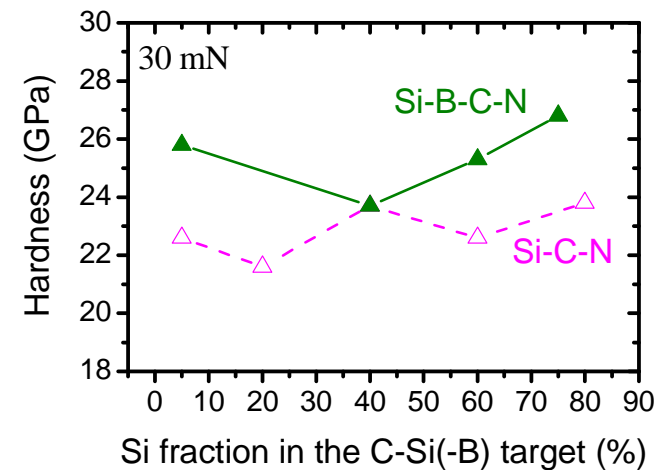
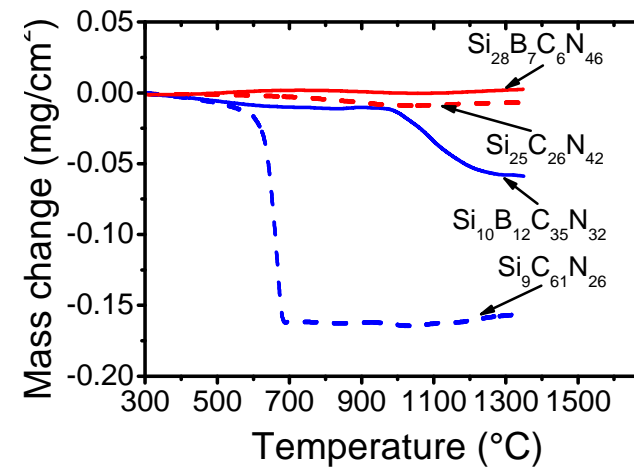
2-4 : M=Ti \rightarrow M=Zr \rightarrow M=Hf: effect on crystallinity

2-5 : M=Ti \rightarrow M=Zr \rightarrow M=Hf: effect on properties

Phenomenon 1-1 (SiBCN): effect of B content

B incorporation into **SiCN** (at **high Si/C** or **low Si/C**):

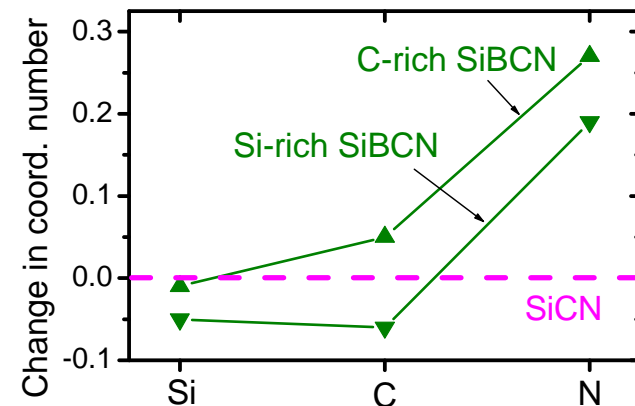
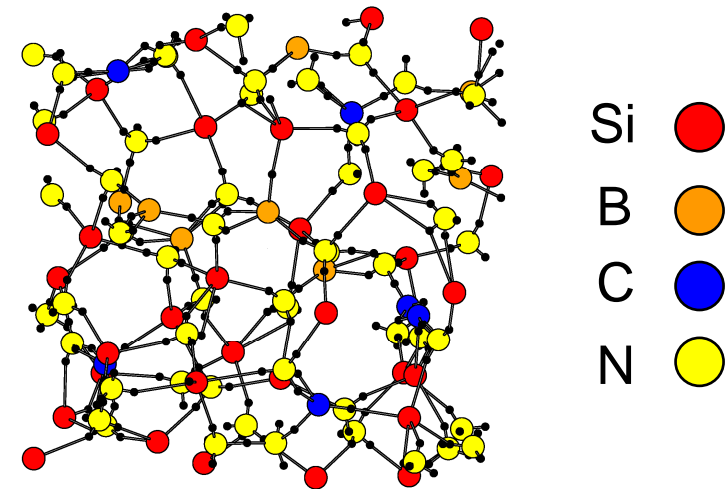
- better thermal stability
- higher hardness



Phenomenon 1-1 (SiBCN): effect of B content

Explanation of hardness and stability after B incorporation:

- structures predicted by liquid-quench ab-initio simulations
- high affinity of B to N
↓
some N electrons are **lonepairs in SiCN**, but **bonding el. in SiBCN**
↓
higher N coordination in SiBCN
↓
lower rate of N₂ formation,
longer bond lifetimes (not shown)



Phenomenon 1-1 (SiBCN): effect of B content

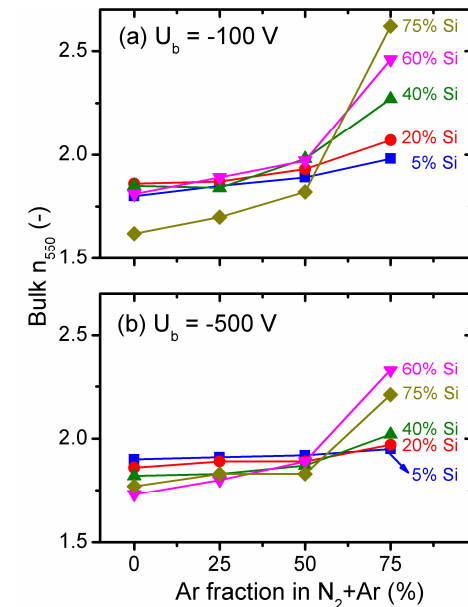
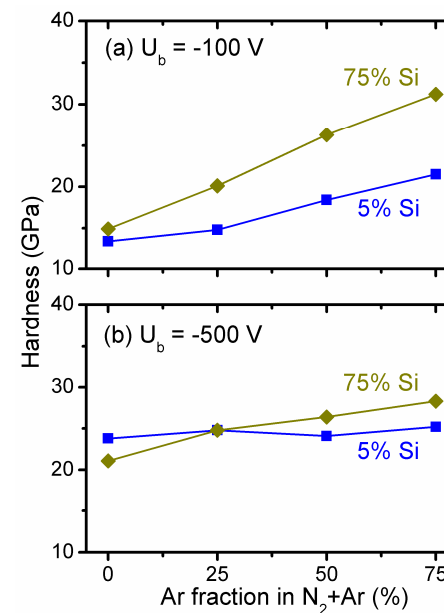
Sputtering of $\text{Si}_x(\text{B}_4\text{C})_{1-x}$ targets: **densification** (hardness, refractive index) is different for **B₄C-rich** and **Si-rich** films

- **B₄C-rich SiBCN:**

best densification by high-energy (500 eV) nitrogen ions

- **Si-rich SiBCN:**

best densification by medium-energy (100 eV) argon ions



- Related also to the Si role during Ar^+ implantation (next slide)

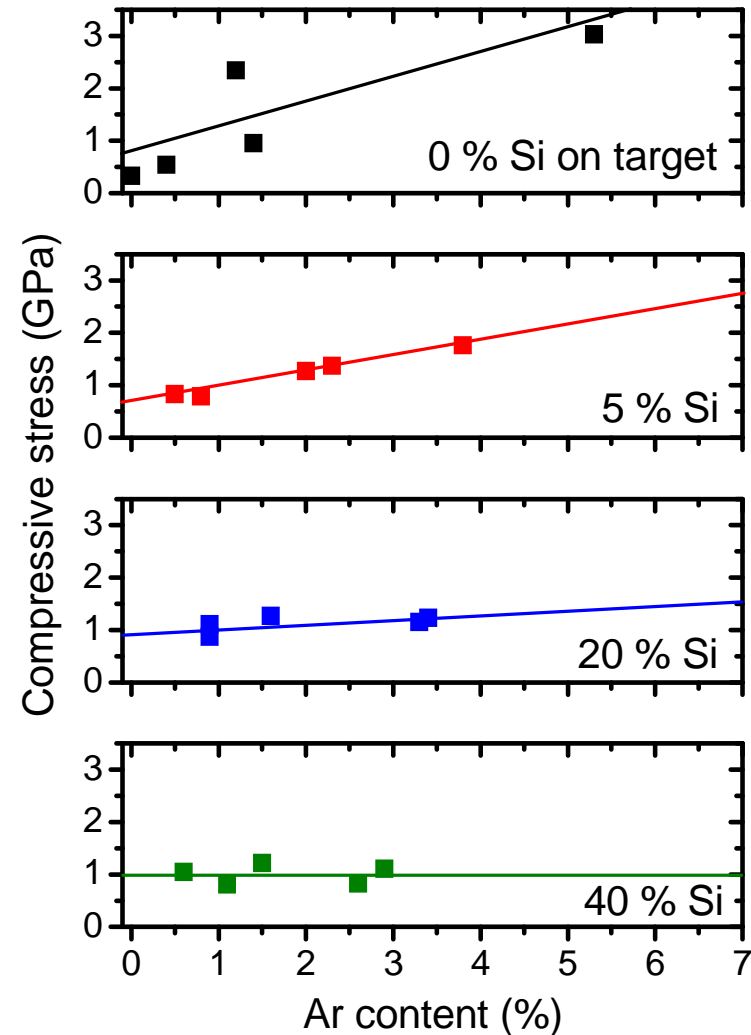
Phenomenon 1-2 (SiBCN): compressive stress

BCN sputtered in N_2+Ar :

- high compressive stress due to implanted Ar^+

Increasing Si content:

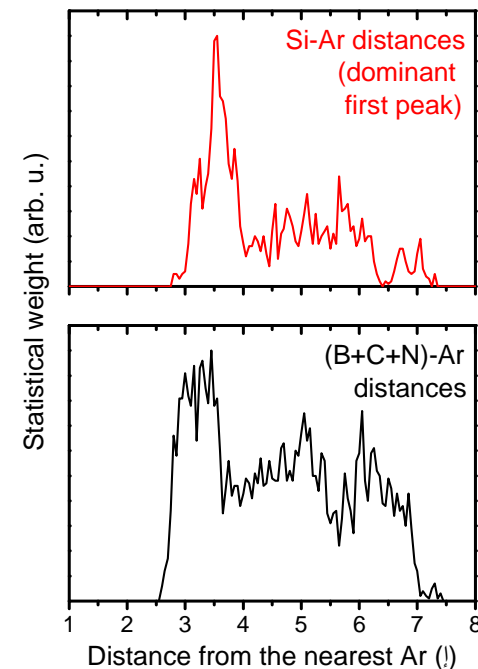
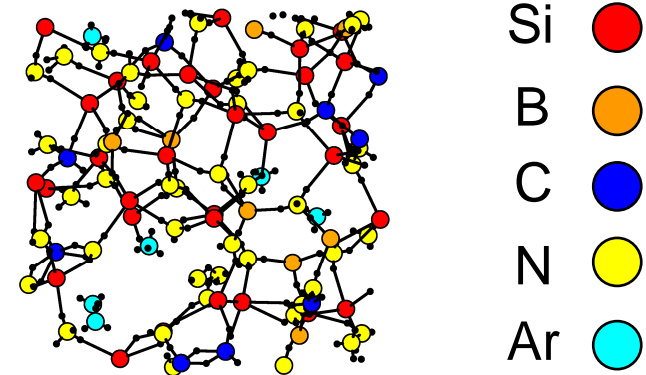
- stress relaxation (decreasing slope of the stress-Ar content dependence)



Phenomenon 1-2 (SiBCN): compressive stress

Explanation of stress relaxation after Si incorporation:

- again, structures predicted by ab-initio simulations
- short B/C/N bonds \times long Si bonds
↓
surrounding the Ar-containing voids by longer and more flexible Si bonds leads to lower energy penalty
↓
low-stress networks with **Si-rich zones segregated around Ar**



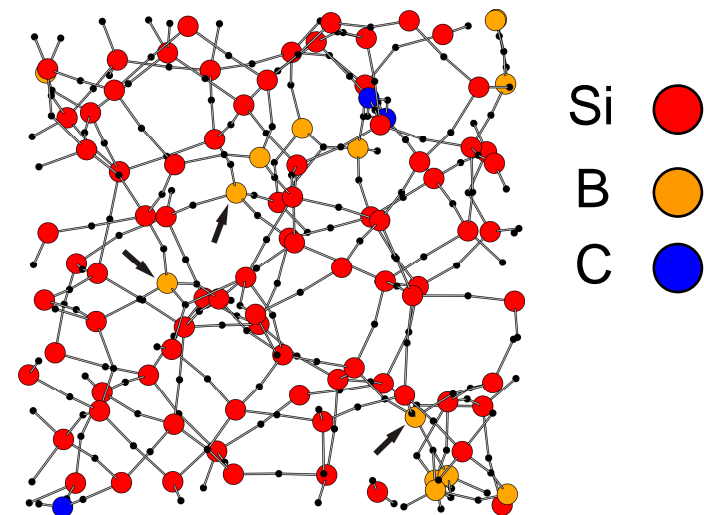
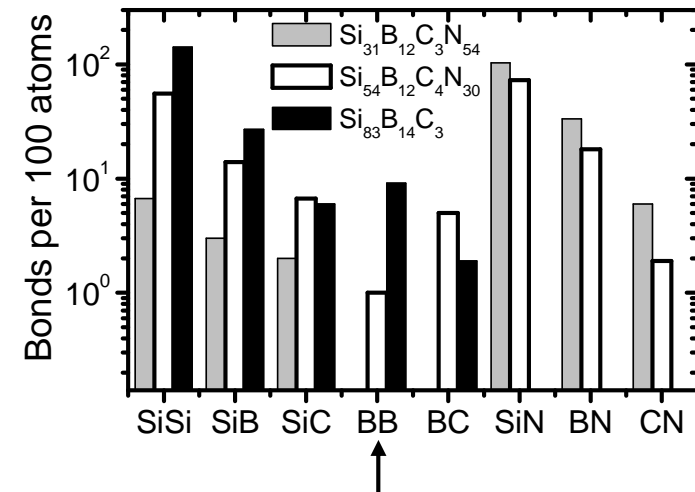
Phenomenon 1-3 (SiBCN): formation of B-rich zones

N-rich SiBCN:

- homogeneous
(SiN, BN, CN bonds)

Replacement of N by Si:

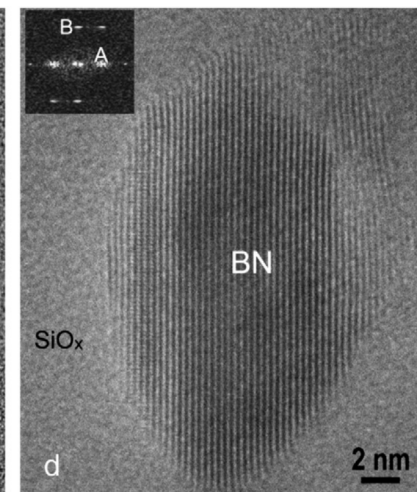
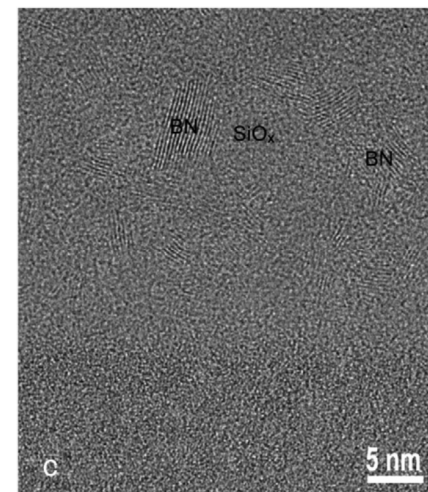
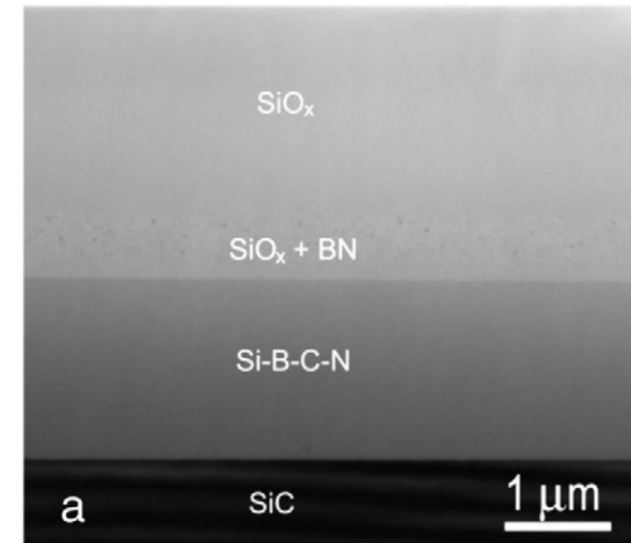
- steeply increasing number of BB bonds
- B atoms nevertheless trapped in a-Si have coordination of 4 (similarly to B dopants in c-Si)



Phenomenon 1-4 (SiBCN): high- T oxidation

SiBCN annealed in air up to 1700 °C:

- amorphous SiO_2 -based top layer
+
transition layer with **BN nanocrystals**
in amorphous SiO_2 -based matrix
+
original bulk layer of SiBCN (on SiC)
- BN-rich transition layer is
another barrier for O_2 diffusion
↓
higher oxidation resistance
of SiBCN compared to SiCN



Phenomenon 1-5 (SiBCN): room-*T* oxidation

80 SiBCN coatings oxidizing at room-*T* for 12 years

two information in one box: effect of substrate bias

- bottom: B_2O_3 layer can protect bulk material
- top: SiO_2 layer can protect bulk material
- medium compositions: $Si_xB_yO_z$ (B constitutes impurities, not oxide in its own right) can NOT protect bulk material

Si _x (B ₄ C) _{1-x} sputter target composition	75% Si	resistant	resistant	resistant	resistant
	60% Si	resistant	resistant	resistant	resistant
	40% Si	ox. barrier / complete ox.	oxidation barrier	resistant	resistant
	20% Si	ox. barrier / complete ox.	ox. barrier / complete ox.	complete oxidation	resistant / ox. barrier
	5% Si	resistant / ox. barrier	resistant / ox. barrier	oxidation barrier	oxidation barrier
		0% Ar	25% Ar	50% Ar	75% Ar
N ₂ +Ar discharge gas mixture composition					

Phenomenon 1-5 (SiBCN): room-*T* oxidation

Bias voltage leading to better ageing resistance

- corelation with growth conditions leading to best densification (Phenomenon 1-1):

bombardment of B₄C-rich SiBCN by 500 eV N₍₂₎⁺

bombardment of Si-rich SiBCN by 100 eV Ar⁺

Si _x (B ₄ C) _{1-x} sputter target composition	75% Si	any U _b	any U _b	any U _b	any U _b
	60% Si	any U _b	any U _b	any U _b	any U _b
	40% Si	-100 V	-100 V	any U _b	any U _b
	20% Si	-100 V	-100 V	-100 V	-100 V
	5% Si	-500 V	-500 V	-500 V	-100 V
		0% Ar	25% Ar	50% Ar	75% Ar
N ₂ +Ar discharge gas mixture composition					

Phenomenon 2-1 (MSiBCN): crystalline phases obtained

ZrBCN deposited in a wide range of $\text{Zr}_x(\text{B}_4\text{C})_{1-x}$ target compositions and N_2+Ar gas mixture compositions

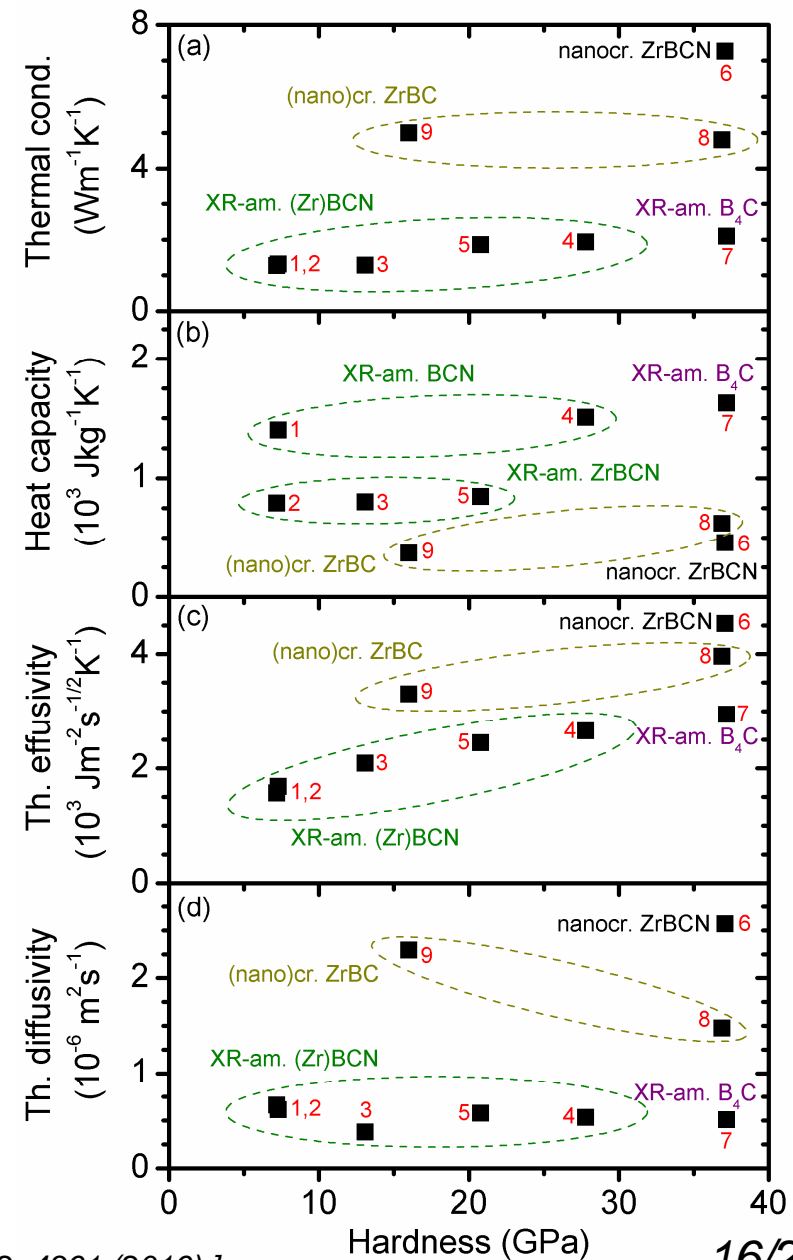
- medium Zr content : **h-ZrB₂** based nanocomposites
- high Zr content : **fcc-ZrN** based nanocomposites
- N is amorphizer (seriously: ZrN-like crystals are more likely at zero N content than at too high N content)
- Si is amorphizer (not shown)

50% N ₂	B ₄₄ C ₁₁ N ₄₂ XR-am. (1)	Zr ₆ B ₃₇ C ₅ N ₄₇ XR-am. (2)	Zr ₁₉ B ₂₄ C ₃ N ₅₂ XR-am. (3)
5% N ₂	B ₆₉ C ₁₆ N ₁₃ XR-am. (4)	Zr ₁₄ B ₅₀ C ₁₃ N ₂₂ XR-am. (5)	Zr ₄₁ B ₃₀ C ₈ N ₂₀ nanocr. cubic (6)
0% N ₂	B ₈₁ C ₁₇ XR-am. (7)	Zr ₂₅ B ₅₇ C ₁₄ cr. hexagonal (8)	Zr ₆₁ B ₂₇ C ₆ nanocr. cubic (9)
	0% Zr	15% Zr	45% Zr

Phenomenon 2-2 (MSiBCN): effect of crystallinity

Nine (Zr)BC(N) films of various structures from the previous slide

- Thermal conductivity & diffusivity & effusivity depend mostly on structure
- Heat capacity depends mostly on composition
- High hardness achieved for (i) crystalline compositions, and (ii) B₄C-rich amorphous compositions



Phenomenon 2-2 (MSiBCN): effect of crystallinity

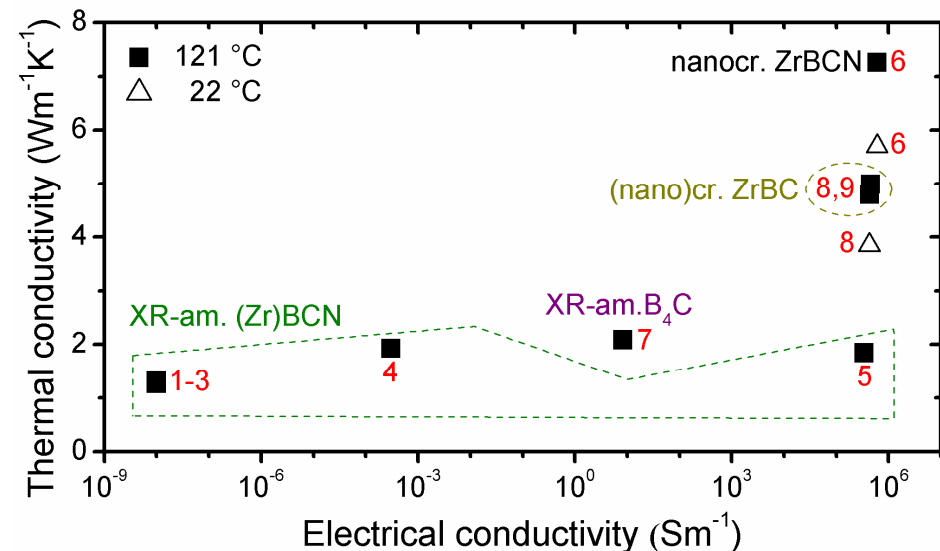
Nine (Zr)BC(N) films of various structures

- Electrical conductivity is high at sufficiently high Zr content and sufficiently low N content (seriously: ZrN is conductive, but N makes ZrBC insulating)



for the same compositions which are crystalline

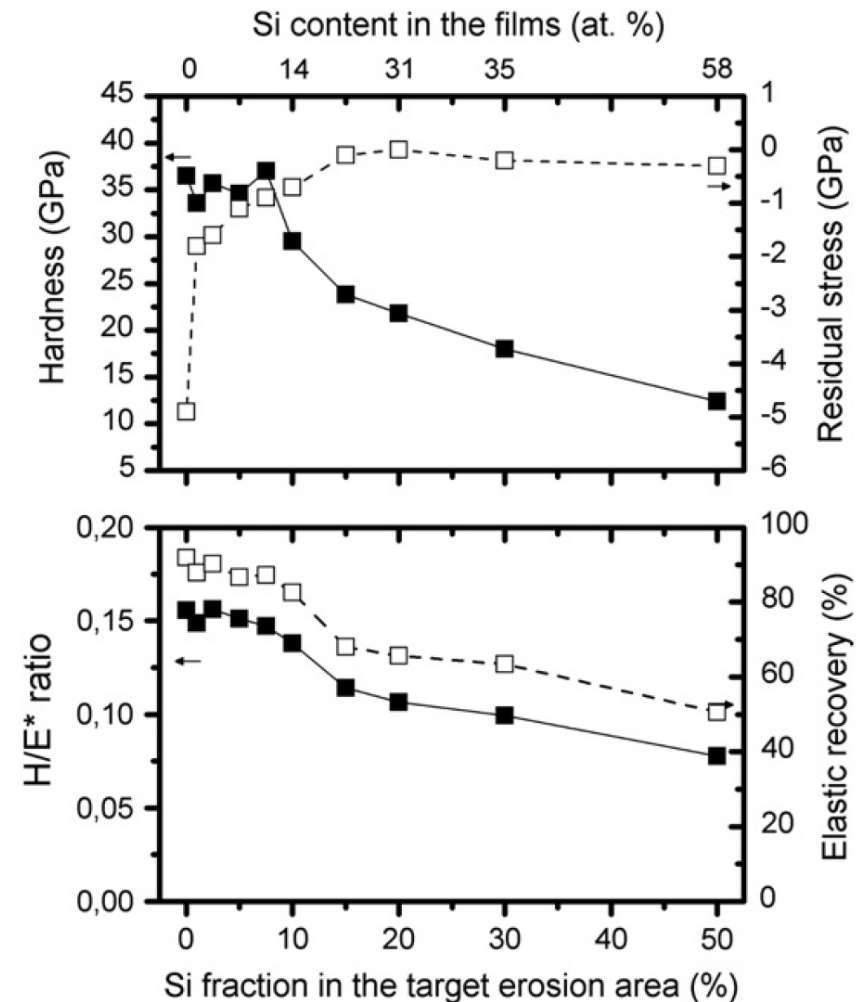
- Difference between thermal conductivities is due to the electronic contribution (well corresponds to the Wiedemann-Franz law)



Phenomenon 2-3 (MSiBCN): compressive stress

HfB₂-based HfSiBC with a wide range of Si contents

- Si-free HfBC : huge compressive stress of 5 GPa
- Si content of 1-10% : stress relaxation to 2 GPa and then 1 GPa at preserved hardness



Phenomenon 2-3 (MSiBCN): compressive stress

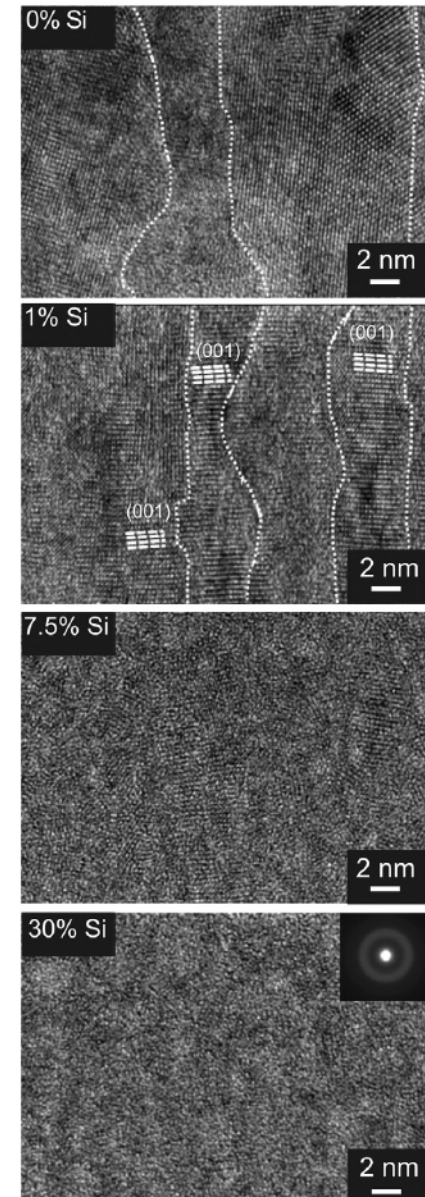
Explanation of stress relaxation by HRTEM

0% Si on target: wide HfB_2 nanocolumns

1% Si on target: narrow HfB_2 nanocolumns
(at a lower stress and preserved H)

7.5% Si on target: isotropic MB_2 nanocrystals
(at even lower stress and still preserved H)

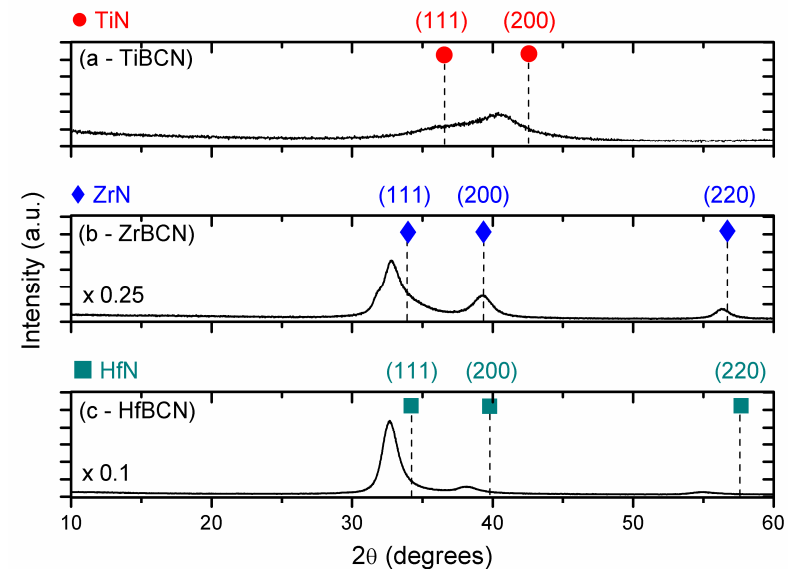
30% Si on target: almost amorphous



Phenomenon 2-4 (MSiBCN): M choice \leftrightarrow crystallinity

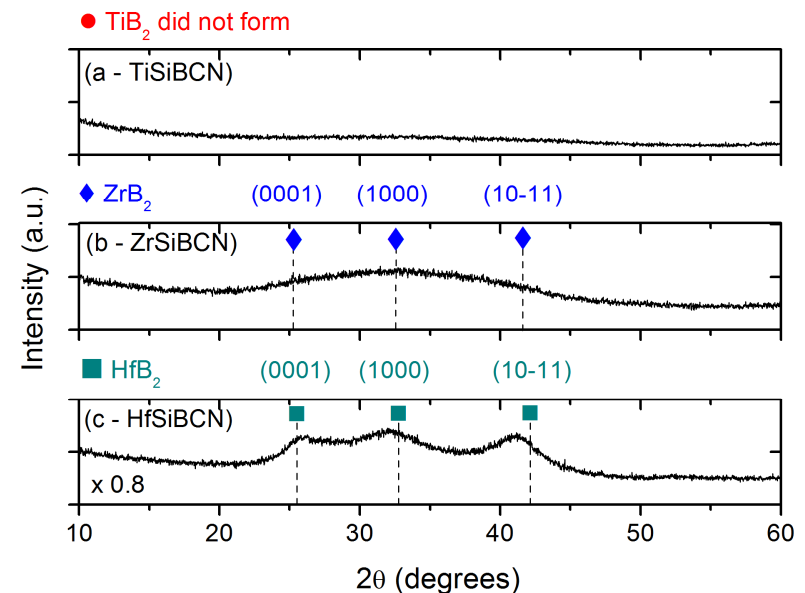
- Sputtering of $M_{0.45}(B_4C)_{0.55}$ in 5% N_2 + 95% Ar :

$M=Ti \rightarrow M=Zr \rightarrow M=Hf$
leads to **stronger MN peaks**
(incl. shifted: solid solutions)



- Sputtering of $M_{15}Si_{20}(B_4C)_{65}$ in 5% N_2 + 95% Ar

$M=Ti \rightarrow M=Zr \rightarrow M=Hf$
leads to **stronger MB_2 peaks**



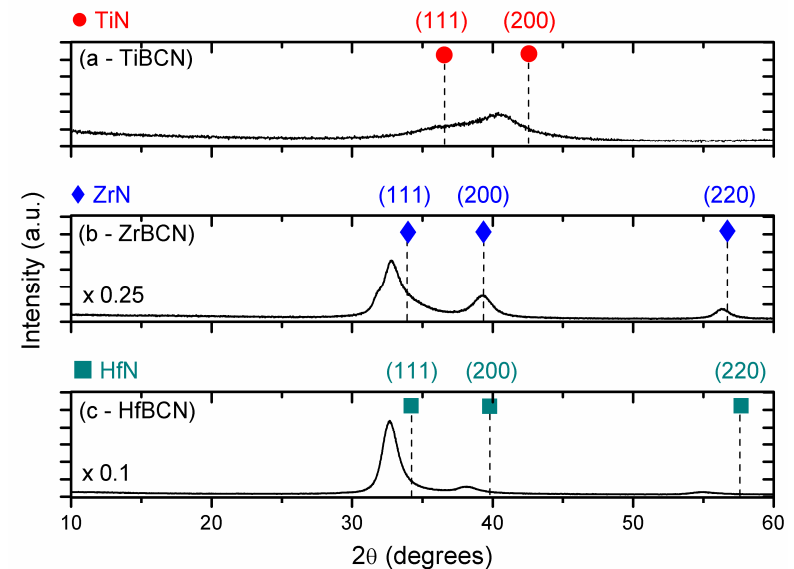
[J. Houska et al., Thin Solid Films 586, 22 (2015)]

[J. Houska et al., Thin Solid Films 616, 359 (2016)]

Phenomenon 2-4 (MSiBCN): M choice \leftrightarrow crystallinity

- Sputtering of $M_{0.45}(B_4C)_{0.55}$ in 5% N_2 + 95% Ar :

$M=Ti \rightarrow M=Zr \rightarrow M=Hf$
leads to **stronger MN peaks**
(incl. shifted: solid solutions)

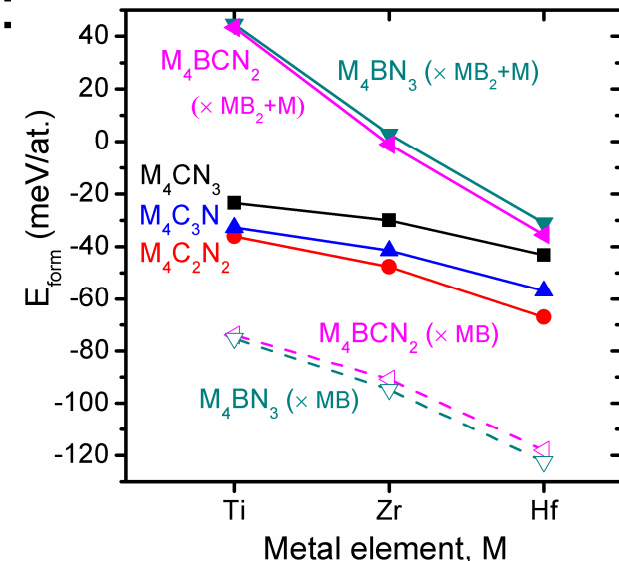


- Explanation by ab-initio calculations:**

$M=Ti \rightarrow M=Zr \rightarrow M=Hf$
leads to decreasing formation energy
of the corresponding solid solutions



crystallization does not
need (so much) segregation



[J. Houska et al., Thin Solid Films 586, 22 (2015)]

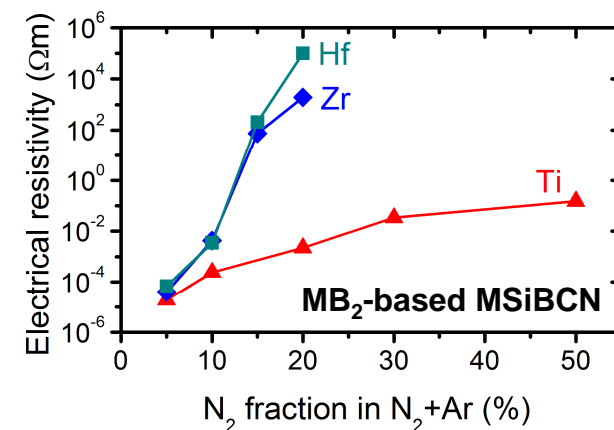
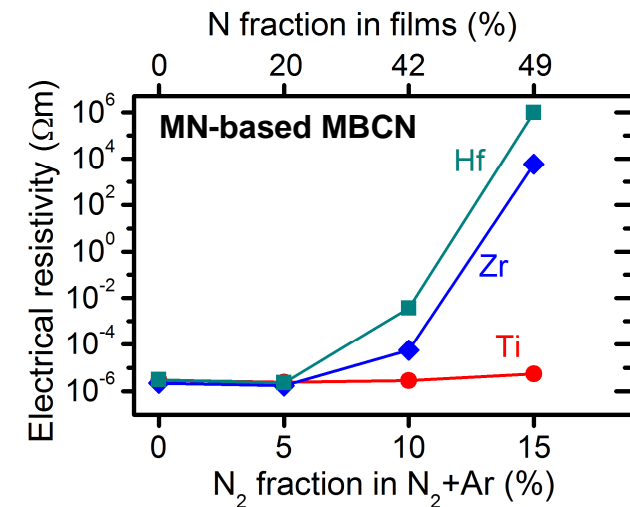
[J. Houska et al., Thin Solid Films 616, 359 (2016)]

Phenomenon 2-5 (MSiBCN): M choice \leftrightarrow properties

High N content

(high importance of M-free amorphous matrix, if there is any):

- $M=\text{Ti} \rightarrow M=\text{Zr} \rightarrow M=\text{Hf}$
leads to **increasing resistivity of MN-based MBCN**
(better crystallinity shown above \Rightarrow conductive crystals encapsulated by insulating amorphous matrix)
- $M=\text{Ti} \rightarrow M=\text{Zr} \rightarrow M=\text{Hf}$
leads to **increasing resistivity of MB₂-based MSiBCN**
(same reason)



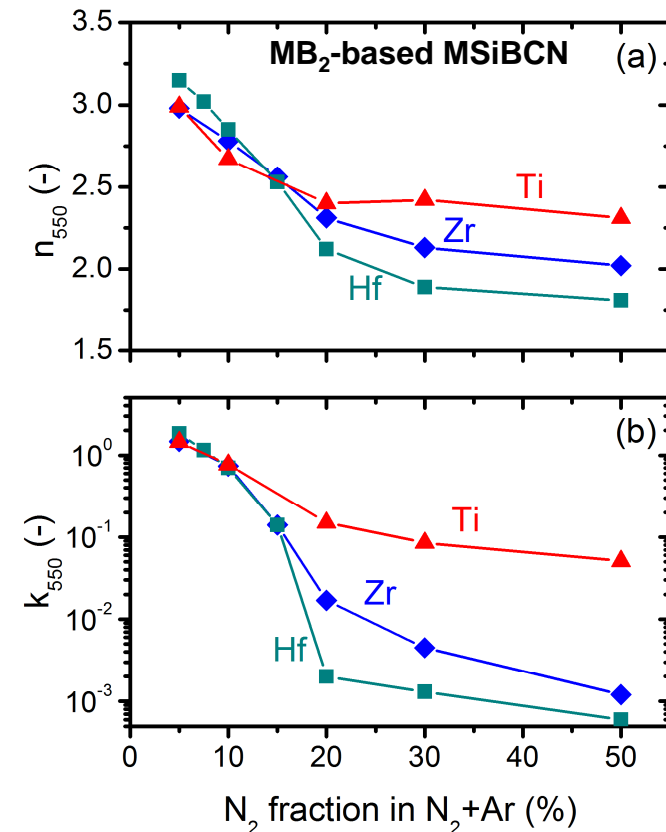
Phenomenon 2-5 (MSiBCN): M choice \leftrightarrow properties

High N content

(high importance of M-free amorphous matrix, if there is any):

- $M=\text{Ti} \rightarrow M=\text{Zr} \rightarrow M=\text{Hf}$
leads to **decreasing refractive index and extinction coefficient of MB₂-based MSiBCN**

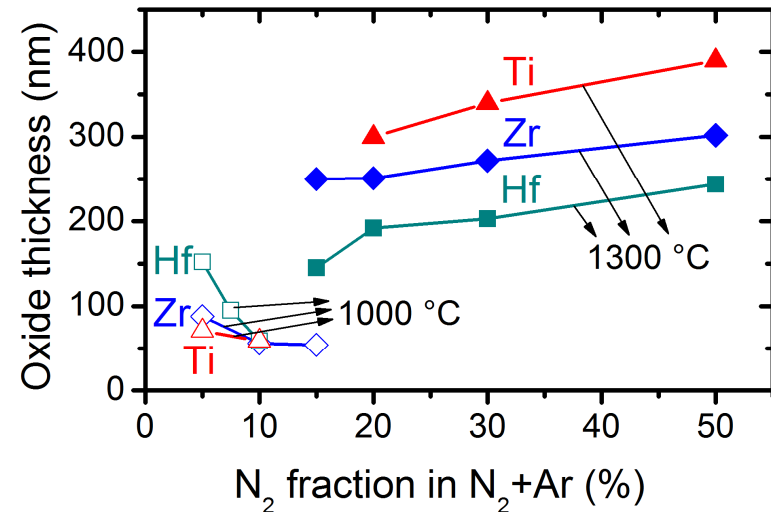
(complementary to the resistivity shown above: more conductive material is less transparent)



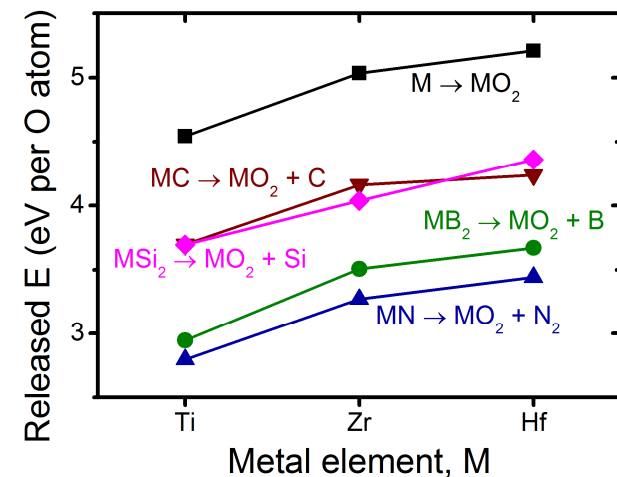
Phenomenon 2-5 (MSiBCN): M choice \leftrightarrow properties

- $M=\text{Ti} \rightarrow M=\text{Zr} \rightarrow M=\text{Hf}$
leads to **worse oxidation resistance of M-rich N-poor** MB₂-based MSiBCN

(in agreement with ab-initio calculations: motivation to oxidize M-based phases)



- $M=\text{Ti} \rightarrow M=\text{Zr} \rightarrow M=\text{Hf}$
leads to **better oxidation resistance of M-poor N-rich** MB₂-based MSiBCN



Conclusions

- **amorphous SiBCN:**
thermal stability (1700 °C), oxidation resistance (1500 °C),
hardness (44 GPa), transparency ($k_{550\text{nm}} = 2 \times 10^{-4}$),
resistivity (from insulating to $10^1 \Omega\text{m}$), etc.
- **amorphous or MB₂-based or MN-based MSiBCN:**
wider range of resistivity (from insulating to $10^{-6} \Omega\text{m}$), etc.
- effect of B and MB₂ on materials properties explained
- compressive stress relaxation in SiBCN or MB₂ explained
- effect of Ti/Zr/Hf choice on structure and properties explained